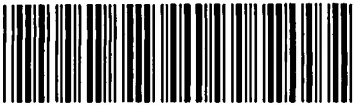


Search Notes

Application/Control No.

10/716,879

Examiner

Alex Liew

Applicant(s)/Patent under
Reexamination

SCHEIER ET AL.

Art Unit

2624

SEARCHED

| Class | Subclass | Date | Examiner |
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INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| 345/163-167, 179-183 limited to text search | 6/23/2007 | AL |
| 382/106, 115-118, 124-127, 154, 179-183 limited to text search | 6/23/2007 | AL |
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